

<b>Modified Form PTO-1449</b> Page 1 of 1	<b>U.S. SERIAL NO.</b> 12/037,889	<b>ART UNIT</b> 2884
<b>LIST OF PATENTS AND PUBLICATIONS STATEMENT</b>	<b>FILING DATE</b> February 26, 2008	<b>ATTORNEY DOCKET</b> P180-US
	<b>FIRST NAMED INVENTOR</b> Fiona A. HARRISON	<b>EXAMINER NAME</b> TANINGCO, Marcus H.

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	ISSUE OR PUBLICATION DATE	PATENTEE OR APPLICANT	FILING DATE
	6,337,117	January 8, 2002	MAENOSONO et al.	June 30, 1999

**FOREIGN PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	COUNTRY	PUBLICATION DATE	PATENTEE OR APPLICANT	TRANSLATION YES/NO
	02/18058	WO	March 7, 2002	RIJN VAN et al.	No

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<u>EXAMINER</u>	<u>DATE CONSIDERED</u>

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